Abstracts

Robust Model Parameter Extraction Using Large-Scale Optimization Concepts

J.W. Bandler, S.H. Chen, S. Ye and Q.J. Zhang. "Robust Model Parameter Extraction Using Large-Scale Optimization Concepts." 1988 MTT-S International Microwave Symposium Digest 88.1 (1988 Vol. I [MWSYM]): 319-322.

A robust approach to model parameter extraction is presented. This approach utilizes multi-bias measurements and dc device characteristics. Novel automatic decomposition concepts for large-scale optimization are used to detect possible model topology deficiencies. Powerful l/sub 1/ optimization is employed with adjoint analyses for both dc and ac sensitivities.

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